

Notice of References Cited	Application/Control No. 10/633,193		Applicant(s)/Patent Under Reexamination KUO ET AL.	
	Examiner Edwin A. León		Art Unit 2833	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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<input checked="" type="checkbox"/>	B	US-5,871,369 A	02-1999	Obayashi et al.	439/495
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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